

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under  
Reexamination  
HEUVELMAN, JEROEN

Examiner

Christopher M. Lambrecht

Art Unit

2611

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2001/0042246 A1	11-2001	YUEN et al.	725/1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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**FOREIGN PATENT DOCUMENTS**

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